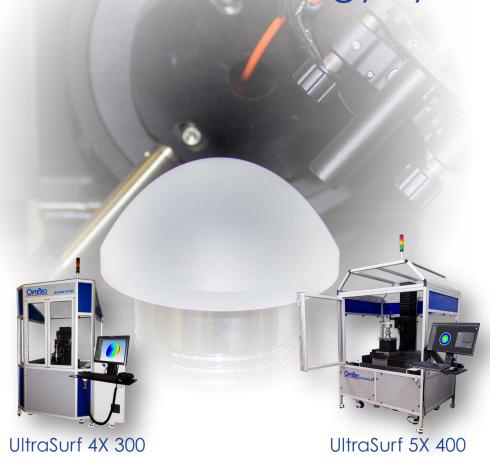


UltraSurf™ Non-Contact Metrology Systems

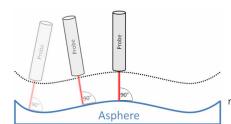


Innovative Machines for Precision Optics and Technical Ceramics

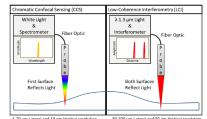


A metrology solution for today's requirements.

Advancements in optical manufacturing technology have motivated optical designers to implement steep aspheres, high departure surfaces, and freeform optics into their systems. Expand your metrology capabilities and take on more challenging jobs with confidence with the UltraSurf non-contact metrology system. UltraSurf is a fast, precise, and reliable solution to qualify the form and figure of ANY asphere up to 400mm in diameter, as well as other complex optical components such as acylinders, freeforms and more. With multiple non-contact probes available, companies can safely measure radius, surface form, center thickness and wedge - all in one measurement.



The measuring probe is scanned over the optical surface while maintaining perpendicularity and a constant focal offset. The probe utilizes absolute distance to resolve metrology challenges such as step heights.



Multiple probe technologies are available on UltraSurf.
Each probe has its advantages relative to the material properties, surface finish, and figure error of an optical component.

High Performance Machines

Engineered for precision and repeatability



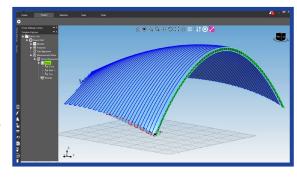


Intelligent Software Technology

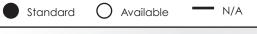
UltraSurf Software: User-friendly yet highly capable



- Many options for defining the surface of the optic to be measured
- Easy to set up non-rotationally symmetric (freeform) optics with on-machine alignment by measuring datums
- Optimized data acquisition for fast 2D and 3D measurements
- Full control of analysis process and ability to export data to several file formats



Capabilities



UltraSurf 4X 300: 4-axis non-contact metrology



Standard Features:

- Optical pen for measuring single surface to 0.3 um PV
 UltraSurf Software for analyzing measurements
 - 1 software for analyzing measurements
 - Optional Features:

 Optical pen for dual-surface scanning

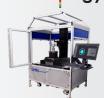
Planos Spheres Aspheres Acylinders Prisms Freeforms Sphere & asphere part size limit UltraSurf 4X 300 Omm Ø S000mm Ø

Cylinders Acylinders

Prisms

Freeforms

UltraSurf 5X 400: 5-axis non-contact metrology

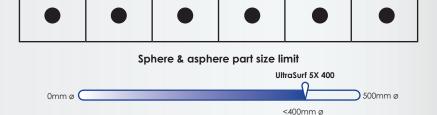


Standard Features:

Optical pen for measuring single surface to 0.3 um PV
 UltraSurf Software for analyzing measurements

Optional Features:

Optical pen for dual-surface scanning
Extended Z-Axis Travel to 600mm



Aspheres

Typical Asphere Measurement Times

Planos

Ø50 mm 5 mm sag



245,000 data points 10 mm sag

Ø100 mm

600,000 data points Ø150 mm 15 mm sag

Spheres

15 min

1,150,000 data points Ø200 mm 20 mm sag



1,300,000 data points

Ideal for a wide range of applications:

Complex geometries:

- Steep aspheres (1)
- Axicons (2)
- Acvlinders
- Freeform optics

A variety of materials:

- Optical glasses
- Technical ceramics
- Crvstals
- Metals (3)

Different surfaces:

- Ground surfaces
- Polished Surfaces
- Diamond-turned surfaces (4)
- High or low reflectivity









Specifications*

	UltraSurf 4X 300	UltraSurf 5X 400
Travels X - Axis Travel Y - Axis Travel Z - Axis Travel B - Axis Travel C- Axis Travel	300 mm (11.8") 6 mm (0.24") 140 mm (5.5") +/- 120° 360° Continuous	400 mm (15.7") 200 mm (7.87") 200 mm (7.87") (600 mm optional) +/- 120° 360° Continuous
Resolution Linear Rotary	5 nm .05 arc-sec	5 nm .05 arc-sec
Maximum Velocity Linear Rotary Max Scanning Speed**	Up to 20 mm/sec 66 RPM 1,000 Hz	Up to 20 mm/sec 22 RPM 1,000 Hz

^{*} Specifications subject to change. Contact OptiPro for the latest specifications.
** 1,000 Hz with appropriate probe configuration

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